



Hardness Testing Equotip Live Leeb D

Portable Leeb D hardness inspection



Innovation

Ultra-portable, intelligent Leeb D probe, coupled to IoT and storage data backup ecosystem with a clean user-interface. Software enables you to share and access the data from anywhere.



Efficiency

Intuitive and efficient user interface to facilitate each step of your inspection. The audio output of readings lets you keep the mobile in your pocket for a more streamlined workflow.



Reliability

Synonymous with Proceq's reliability and legendary status with durable and accurate Leeb products from the inventor of Leeb method.



Software / Workspace App

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|---------------------------------|---|
| | iOS app including free updates Hotspots with predefined shortcuts Audio output of readings allow to keep mobile in the pocket On-screen guides Verification and calibration of information for higher reliability |
| Instrument Firmware | |
| PC Software | Web browser-based Equotip Live solution |
| Display | Any compatible iOS device (iPod Touch, iPhone iOS 9.0 and higher) |
| Memory | Memory of the iOS device |
| Custom conversion curves | Yes, one point shift |
| Cloud features | Cloud storage (matching that of Apple® iOS device) Cloud-enabled Logbook Cloud-based report generation |
| Mobile and web features | Voice read-out of each impact (Apple® iOS app only) Logbook with geolocation, audio, image, and text annotations Export to PDF and CSV Series statistics |
| User interface languages | English, Chinese, French, German, Italian, Japanese, Korean, Portuguese, Russian, Spanish |



Processing Unit / Sensor

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|--|------------------------------|
| Native Scale | HLD |
| Available Scales | HB, HV, HRB, HRC, HS, MPA |
| Available Probes | Leeb D |
| Average Roughness Ra (µm / µinch) | 2 / 80 |
| Connections | USB for charging and updates |
| Minimum Mass (kg / lbs) | 0.05 / 0.2 |
| Minimum Thickness (mm / inch) | 3 / 0.12 |
| Measuring Range | 150 - 950 HL |
| Measuring Accuracy | ± 4 HL (0.5% at 800 HL) |
| Coefficient of variation | ± 4 HL (0.5% at 800 HL) |